Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/538,498	ZHANG ET AL.
Examiner	Art Unit
Stuart W. Snyder	1648

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Dialog: Magnetic or paramagnetic, microbead or microparticle or microsphere, separat? or isolat?	12/3/2007	sws
EAST: Magnetic or paramagnetic, microbead or microparticle or microsphere, separat? or isolat?; inventors	12/3/2007	sws
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